PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Mitsutoshi MIYASAKA Group Art Unit: 2815

Application No.: 10/786,151 Examiner: P. BUDD

Filed: February 26, 2004 Docket No.: 118490

For: COMPLEMENTARY THIN FILM TRANSISTOR CIRCUIT, ELECTRO-OPTICAL

DEVICE, AND ELECTRONIC APPARATUS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed more than three months after the U.S. filing date and after the mailing date of a Final Rejection, Notice of Allowance, or other action that closes prosecution (e.g., Quayle Action), but before payment of the Issue Fee. The fees associated with this filing under 37 C.F.R. §1.17(i) are being paid electronically with this filing. The Commissioner is hereby authorized to charge any additional fee (or credit any overpayment) associated with this communication to Deposit Account No. 15-0461.
 - a. I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.

 37 CFR §1.97(e)(1).
- 2. An English language Abstract of one or more non-English language reference is attached. See References 2-3.

- 3. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy. See Reference 2.
- 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- \boxtimes 5. Reference $\underline{1}$ corresponds to reference $\underline{2}$.

Respectfully submitted,

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JAO:SPC/jls

Date: July 12, 2007

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE
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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 118490			APPLICATION NO. 10/786,151			
INFORMATION DISCLOSURE STATEMENT						į				
(Use several sheets if necessary)			APPLICANT Mitsutoshi MIYASAKA							
			FILING DATE February 26, 2004			GROUP 2815				
U.S. PATENT DOCUMENTS										
Examiner Initials	Cite No.			te	e Name					
	1	5,824,574	10/20/19	98	Yamazaki et al.					
FOREIGN PATENT DOCUMENTS										
Examiner Initials	Cite No.	Document Number	Da	ite	Country		With English Abstract	With English Translation		
	2	JP-A-08-321466	12/03/19	96	Japan		х	х		
	3	JP-A-01-264215	10/20/19	89	Japan		х			
			OTHER D	OCUME	NTS					
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)								
	4	Van der Wilt, Paul, van Dijk, B.D., Be	ertens, G.J.,	Ishihara,	R., and Beenakker, C.I.M., Form	ation of Lo	cation-Contr	olled		
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EXAMINER	MINER DATE CONSIDERED									
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										

Date: July 12, 2007